

<p style="text-align: center;">O I P E INFORMATION DISCLOSURE CITATION <small>(Use several sheets if necessary)</small> <i>SEP 27 2004</i> <i>PATENT & TRADEMARK</i></p>				ATTY DOCKET NO.		APPLICATION NO.
				BUR920040089US1		
				APPLICANT(S) Voldman et al.		
				FILING DATE		GROUP ART UNIT Unknown
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WLL	4,578,128	03/25/86	Mundt et al.	—	—	
WLL	4,486,266	12/04/84	Yamaguchi	—	—	
WLL	4,862,233	08/29/89	Matsushita et al.	—	—	
WLL	4,729,006	03/01/88	Dally et al.	—	—	
WLL	4,656,730	04/14/87	Lynch et al.	—	—	
U.S. PATENT APPLICATION PUBLICATIONS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WLL	2002/0135024	09/26/02	Logan et al.	—	—	
WLL	2003/0205765	11/06/03	Masuoka	—	—	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES
WLL	JP63-304661	12/12/88	Japan	—	—	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
WLL		Voldman et al., "Retention Time and Soft Error Rate Improvement by Tailoring Well Doping in Trench Dram Cells", IBM Technical Disclosure Bulletin, Vol. 33, No. 1B, 1990, pp. 35-36.				
WLL		L.A. Nesbit, "Method of Forming Shallow Trench Isolation With Selectively Doped Sidewalls, Vol. 31 No. 2, 1988, pp. 418-420.				
EXAMINER	<i>WLL</i>			DATE CONSIDERED <i>3/24/08</i>		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

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				Voldman et al. FILING		GROUP ART Unknown	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
WLL	4,926,233	05/15/90	Hutter	—	—		
WLL	5,067,002	11/19/91	Zdebel et al.	—	—		
WLL	5,612,242	03/18/97	Hsu	—	—		
WLL	6,514,833	02/04/03	Ishida et al.	—	—		
WLL	6,600,199	07/29/03	Voldman et al.	—	—		
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Webb T. Lawler Jr.</i>				DATE CONSIDERED <i>3/24/05</i>			
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				Voldman et al.			
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>WCC</i>	5,780,353	07/14/98	Omid-Zohoor	—	—		
<i>WCC</i>	6,518,628	01/11/03	Krautschneider et al.	—	—		
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>WCC</i>							
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
<i>WCC</i>						YES	NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
EXAMINER <i>Walt L. Labay Jr.</i>				DATE CONSIDERED <i>3/24/05</i>			
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